Docket No.

210148US99

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: JAMAL RAMDANI ET AL

SERIAL NO:

GAU:

EXAMINER: SIMKOVIC

2812

FILED:

FOR:

JUNE 21, 2002-

INTERFACE WITH SILICON

METHOD FOR FABRICATING A SEMICONDUCTOR STRUCTURE INCLUDING A METAL OXIDE

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references were submitted in application Serial No. 09/908,888 according to the attached copy of a Granted Petition. This application contains related subject matter.
- A check is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- A check is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

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OBLON, SPIVAK, McCLELLAND,

Respectfully submitted,

MAIER & NEUSTADT, P.C.

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SHEET OF 5 SERIAL NO. ATTY DOCKET NO. U.S. DEPARTMENT OF COMMERCE Form PTO 1449 PATENT AND TRADEMARK OFFICE (Modified) 09/885,409 210148US99 **APPLICANT** LIST OF REFERENCES CITED BY APPLICANT Jamal RAMDANI, et al. **GROUP FILING DATE** 2812 June 21, 2001 **U.S. PATENT DOCUMENTS FILING DATE** SUB **DOCUMENT EXAMINER CLASS** DATE NAME **CLASS** IF APPROPRIATE INITIAL NUMBER 06/18/96 Macdonald et al. UT 5,528,209 12/07/99 Vawter et al. UV 5,998,781 08/29/00 UW 6,110,813 Ota et al. 09/17/02 UX 6,452,232 B1 Adan 04/11/00 Koh UY 6,049,110 Hu et al. 09/24/96 UZ 5,559,368 05/21/02 VA 6,392,253 B1 Saxena Davis et al. 5,585,288 12/17/96 **VB** 12/07/93 Vernon VC 5,268,327 Nabatame et al. VD 6,198,119 B1 03/06/01 Miyata et al. 09/05/00 VΕ 6,113,225 Grudkowski et al. 5,262,659 11/16/93 **VF** ROOM 6,239,012 B1 05/29/01 Kinsman VG 6,297,598 10/02/01 Wang et al. VH 2002/140012 10/03/02 Droopad VΙ

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Yokoyama et al.

Date Considered

Yokogawa et al.

Yokota et al.

Shanley

Holder

Jewell

Conley

Akiyama

Idaka et al.

Pique et al.

Roeder et al.

Feuer et al.

Takatani et al.

09/12/89

06/27/00

04/16/96

11/05/02

09/22/87

03/16/99

11/12/96

04/23/96

02/14/89

10/15/91

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Examiner

4,866,489

6,080,378

5,508,554

4,695,120

5,882,948

5,574,589

5,510,665

4,804,866

5,057,694

5,635,453

5,719,417

5,998,819

6,477,285 B1

ATTY DOCKET NO.
210148US99

Form PTO 1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

SERIAL NO. 09/885,409

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Jamal RAMDANI, et al.

FILING DATE GROUP

June 21, 2001 2812

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE			
	w	2002/0079576	06/27/02	Seshan						
	VX	5,148,504	09/15/92	Levi et al.						
	VY	2002/0195610 A1	12/26/02	Klosowiak						
	VZ	5,477,363	12/19/95	Matsuda						
- '	WA	5,905,571	05/18/99	Butler et al.						
· ·	WB	5,570,226	10/29/96	Ota						
	wc	5,087,829	02/11/92	Ishibashi et al.		(<u></u>			
	WD	2001/0020278 A1	09/06/01	Saito						
	WE	6,496,469 B1	12/17/02	Uchizaki						
. Vart	WF	5,679,947	10/21/97	Doi et al.			TO 0			
	WG	2001/0036142 A1	11/01/01	Kadowaki et al.			/E			
	WH	5,446,719	08/29/95	Yoshida et al.			カ、島 ロ			
, <u>.</u>	WI	5,831,960	11/03/98	Jiang et al.						
	MJ	5,693,140	12/02/97	McKee et al.			، حکسم			
·	WK	6,376,337 B1	04/23/02	Wang et al.			4 			
	WL	4,177,094	12/04/79	Kroon			4 T			
, , .	WM	5,216,359	06/01/93	Makki et al.						
	WN	6,307,996 B1	10/23/01	Nashimoto et al.						
	wo	5,371,621	12/06/94	Stevens						
<u>.</u>	WP	2002/0145168 A1	10/10/02	Bojarczuk, Jr et al.			-			
	WQ	3,617,951	11/02/71	Anderson						
	WR	5,838,053	11/17/98	Bevan et al.						
	ws	5,684,302	11/04/97	Wersing et al.						
	WT	5,959,308	09/28/99	Shichijo et al.						
	WU	5,362,972	11/08/94	Yazawa et al.						
	wv	5,864,171	01/26/99	Yamamoto et al.						
	ww	5,028,563	07/02/91	Feit et al.						
	wx	5,937,115	08/10/99	Domash						
Examiner	miner					Date Considered				

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

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Jamai RAMDANI, et al.

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SERIAL NO. 09/885,409

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	WY	5,878,175	03/02/99	Sonoda et al.			
	WZ	4,801,184	01/31/89	Revelli			
	XA	5,140,387	08/18/92	Okazaki et al.			
	ХВ	5,410,622	04/25/95	Okada et al.			
	хс	6,064,783	05/16/00	Congdon et al.			
	XD	5,772,758	06/30/98	Collins et al.			
	XE	5,666,376	09/09/97	Cheng			
	XF	5,976,953	11/02/99	Zavracky et al.			
	XG	5,578,162	11/26/96	D'Asaro et al.			4
	XH	5,585,167	12/17/96	Satoh et al.			
	ΧI	5,674,813	10/07/97	Nakamura et al.			BE A
	XJ	5,574,296	11/12/96	Park et al.			
	XK	6,504,189	01/07/03	Matsuda et al.			307
	XL	5,987,196	11/16/99	Noble			下23 四
	XM						8 3 0
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Form PTO 1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

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LIST OF REFERENCES CITED BY APPLICANT

Jamal RAMDANI, et al.

FILING DATE
June 21, 2001

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FOREIGN PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE COUNTRY		TRANSLATION YES NO				
	СВС	EP 1 035 759	09/13/00	Europe					
	CBD	EP 0 860 913	08/26/95	EUROPE					
	CBE	5-232307	09/10/93	JAPAN W/ENGLISH ABSTRACT					
	CBF	5-243525	09/31/93	JAPAN W/ENGLISH ABSTRACT					
	CBG	3-171617	07/25/91	JAPAN W/ENGLISH ABSTRACT					
	СВН	EP 1 089 338	04/04/01	EUROPE					
	СВІ	01 294594	11/28/99	JAPAN (ABSTRACT)					
	СВЈ	05 221800	08/31/93	JAPAN (ABSTRACT)					
	СВК	03-149882	11/07/89	JAPAN					
	CBL	0 614 256	09/07/94	EUROPE					
	СВМ	1 054 442	11/22/00	EUROPE	· ·				
	CBN	0 852 416	07/08/98	EUROPE	.~				
	СВО	WO 02/08806	01/31/02	WIPO					
	СВР	WO 01/59837	08/16/01	WIPO	and the second second				
		62-245205	10/26/87	JAPAN W/ENGLISH ABSTRACT					
		0 600 658	06/08/94	EUROPE	Ø (= ·:π;				
	CBS		02/06/91	EUROPE	6 - 77				
	СВТ	2000-349278	12/15/00	JAPAN (ENGLISH ABSTRACT)	302				
	CBU	***	08/08/89	JAPAN (ENGLISH ABSTRACT)	E S M				
	CBV		10/12/94	EUROPE	8 5 0				
	CBW	0 661 561	07/05/95	EUROPE	3.				
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			APPLICANT								
LIST OF	REFE	RENCES CITED BY APPLICANT	Jamal RAMDANI,	et al.							
			FILING DATE		GROUP						
			June 21, 2001		2812						
		OTHER REFERENCES (Including Author, Title	, Date, Pertinent Pages,	etc.)						
	KKAO	Charles Kittel; "Introduction to	Solid State Physics";	John Wiley & Sons, Inc	. Fifth Edition	ı; pp.	415				
	KKAP	Chyuan-Wei Chen et al; "Liquid-phase epitaxial growth and characterization of InGaAsP layers grown on GaAsP substrates for application to orange light-emitting diodes"; 931 Journal of Applied Physics; 77 (1995) 15 January, No. 2; Woodbury, NY, US; pp. 905-909									
	KKAQ	W. Zhu et al.; "Oriented diamond films grown on nickel substrates"; 320 Applied Physics Letters; 63(1993) September, No. 12, Woodbury, NY, US; pp. 1640-1642									
	KKAR	M. Schreck et al.; "Diamond/Ir/SrTiO3: A material combination for improved heteroepitaxial diamond films"; Applied Physics Letters; Vol. 74, No. 5; February 1, 1999; pp. 650-652									
	KKAS	Yoshihiro Yokota et al.; "Cathodoluminescence of boron-doped heteroepitaxial diamond films on platinum"; Diamond and Related Materials 8(1999); pp. 1587-1591									
	KKAT	J.R. Busch et al.; "LINEAR ELECTRO-OPTIC RESPONSE IN SOL-GEL PZT PLANAR WAVEGUIDE"; Electronics Letters; 13th August 1992; Vol. 28, No. 17; pp. 1591-1592									
	KKAU	R. Droopad et al; "Epitaxial Oxide Films on Silicon: Growth, Modeling and Device Properties"; Mat. Res. Soc. Symp. Proc. Vol. 619; 2000 Materials Research Society; pp. 155-165									
	KKAV	H. Ohkubo et al.; "Fabrication of High Quality Perovskite Oxide Films by Lateral Epitaxy Verified with RHEED Oscillation"; 2419A Int. Conf. on Solid State Devices & Materials, Tsukuba, August 26-28 (1992); pp. 457-459									
	KKAW	Lin Li; "Ferroelectric/Superconductor Heterostructures"; Materials Science and Engineering; 29 (2000) pp. 153-181									
	KKAX	L. Fan et al.; "Dynaamic Beam Switching of Vertical-Cavity Surface-Emitting Lasers with Integrated Optical Beam Routers"; IEEE Photonics Technology Letters; Vol. 9, No. 4; April 4, 1997; pp. 505-507									
	KKAY	Y. Q. Xu. et al.; "(Mn, Sb) dropped-Pb(Zr,Ti)03 infrared detector arrays"; Journal of Applied Physics; Vol. 88, No. 2; 15 July 2000; pp. 1004-1007									
	KKAZ	Kiyoko Kato et al.; "Reduction of dislocations in InGaAs layer on GaAs using epitaxial lateral overgrowth" 2300 Journal of Crystal Growth 115 (1991) pp. 174-179; December 1991									
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	LLAE										
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